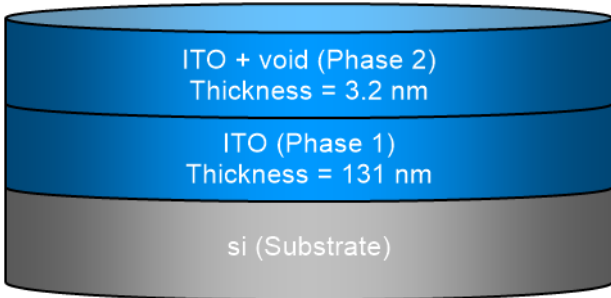


SEA regression report summary

Sample ID
001c 70° 2

Details	
Software and regression log	
Software about	Semilab - Spectroscopic Ellipsometry Analyzer - SEA
Software version	1.7.1
Officially licensed to	MIT
Operator	operator
Date and time of regression	14-07-2021 14:18
Comments	

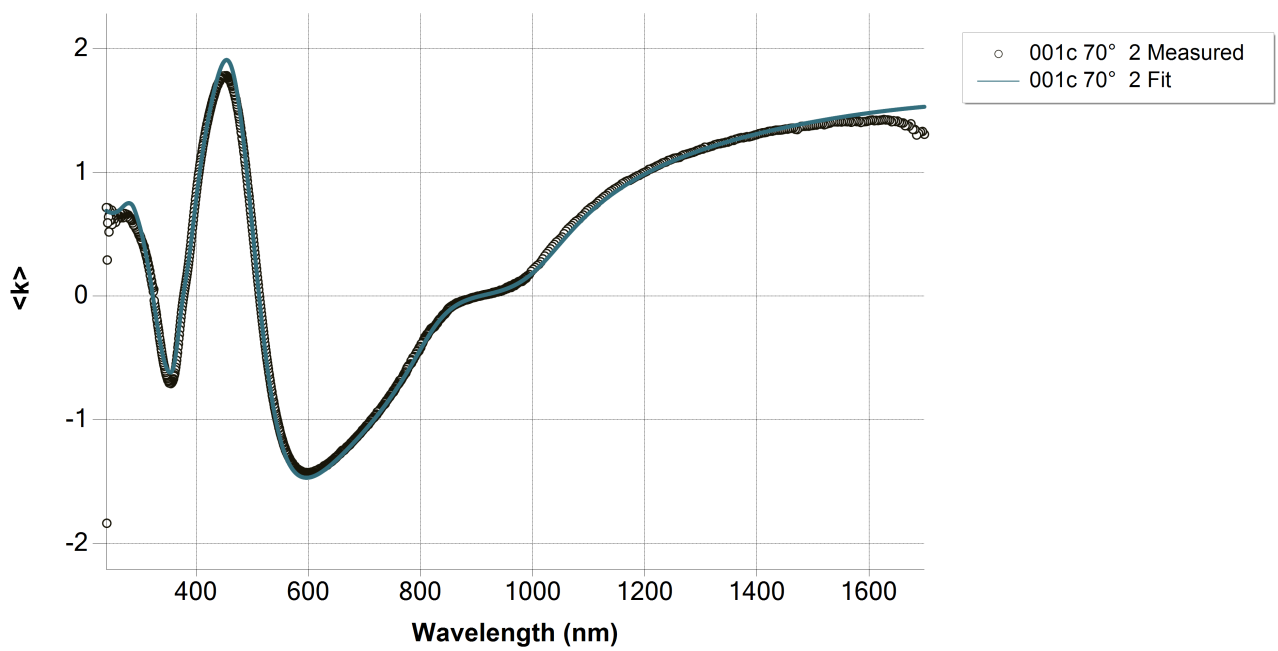
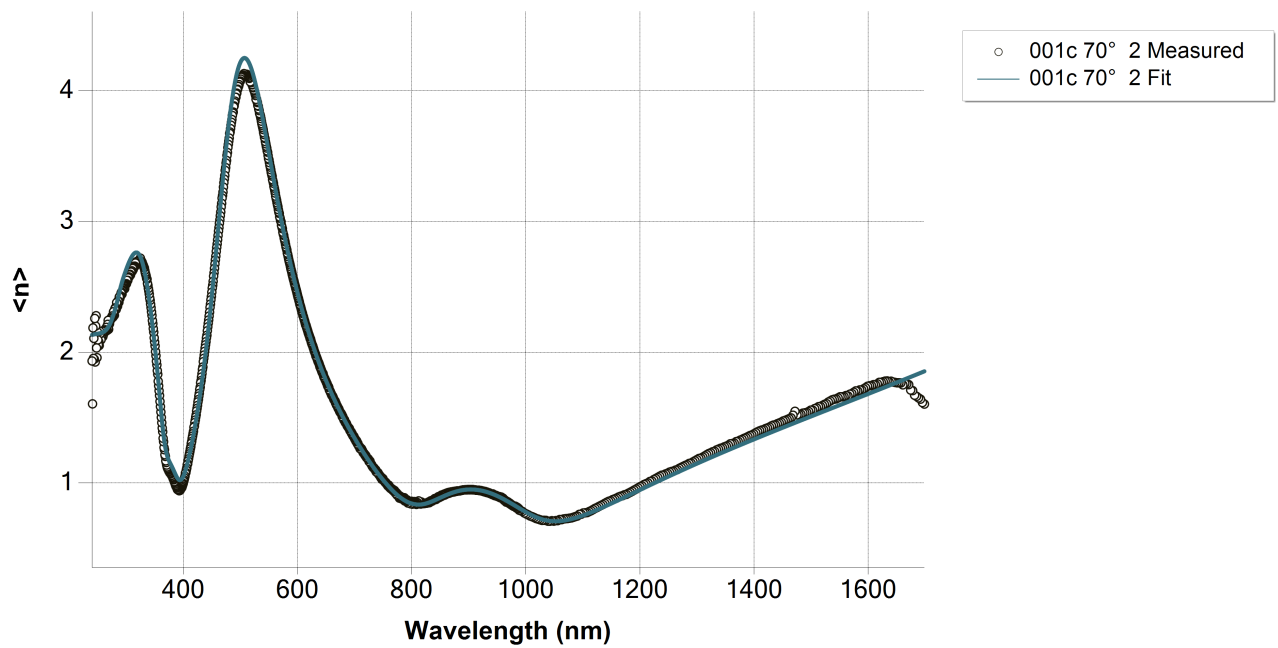
Layer structure	
Overview	
 <p>The diagram shows a cylindrical cross-section of a layered material. It consists of three distinct layers. The top layer is light blue and labeled 'ITO + void (Phase 2)' with a thickness of '3.2 nm'. The middle layer is a darker blue and labeled 'ITO (Phase 1)' with a thickness of '131 nm'. The bottom layer is grey and labeled 'si (Substrate)'.</p>	
Optical model	
Phase 2	ITO + void
Diffusion	
Phase 1	ITO
Dispersion law	Tauc-Lorentz
	Drude

Regression results

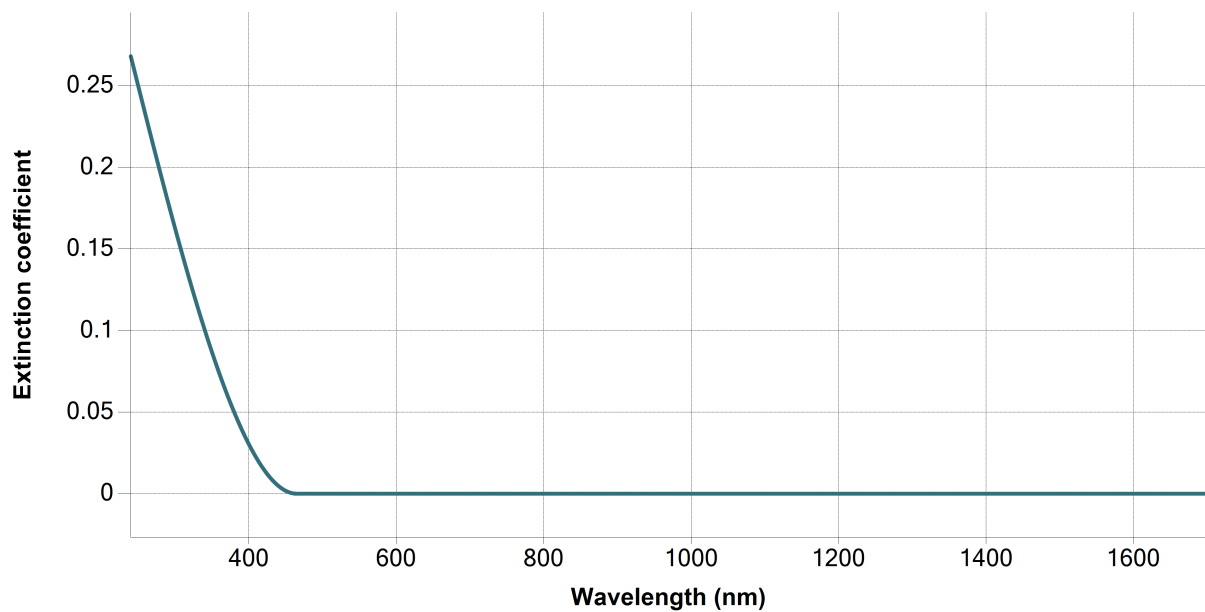
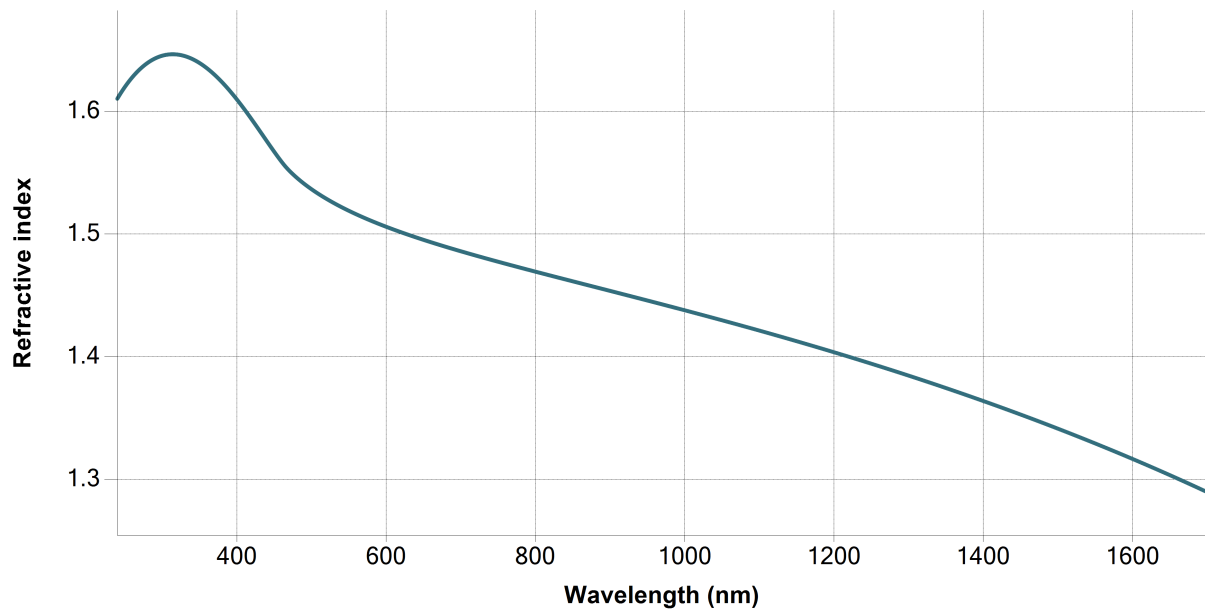
Measurement information				
Measurement file path	C:\Users\emmabat\lito-sil\001c.smdx			
Angle of Incidence	70°			
Regression details				
Regression 1 (EllipsoReflectance)				
Wavelength range	239.84 - 1698.83 nm			
Angle of Incidence	70°			
Fit to	<n>, <k>			
Angular Aperture	0°			
Fit algorithm	LMA			
Results				
Parameters	Value	Fitted	2 σ confidence limit	Unit
Model				
AOI Shift	0			°
Angular Aperture	0			°
Phase 2 (ITO + void)				
Thickness	3.19	X	0.21277	nm
Depolarization coefficient	0.33333			
Concentration 1	0.5			
Concentration 2	0.5			
Phase 1 (ITO)				
Thickness	131.005	X	0.32741	nm
A (eV)	326.06406	X	45.31355	eV
E0 (eV)	9.88552	X	0.33146	eV
C (eV)	49.98148	X	7.87165	eV
Eg (eV)	2.66638	X	0.018835	eV
E_p (eV)	0.92705	X	0.012238	eV
E_Γ (eV)	0			eV
Eps_inf	0			
Derived parameters	Value			
Phase 2 (ITO + void)				
n @ 632.8 nm	1.4987			
k @ 632.8 nm	0			
Phase 1 (ITO)				
n @ 632.8 nm	2.0551			
k @ 632.8 nm	0			
Substrate (si)				
n @ 632.8 nm	3.8811			
k @ 632.8 nm	0.0195			
Drude derived parameters	Value			Unit
Phase 1 (ITO)				
Conductivity (S/m)	∞ ± NaN			S/m
Resistivity (mΩ.cm)	0 ± NaN			mΩ.cm
Resistance (Ω/sq)	0 ± NaN			Ω/sq
N type dopant concentration (at/cm3)	1.5582E+20 ± 4.1142E+18			at/cm3

P type dopant concentration (at/cm3)	2.3062E+20 ± 6.089E+18	at/cm3
N type dopant mobility (cm2/Vs)	∞ ± NaN	cm2/Vs
P type dopant mobility (cm2/Vs)	∞ ± NaN	cm2/Vs
Fit quality		
R^2	0.99434	
RMSE	0.07088	

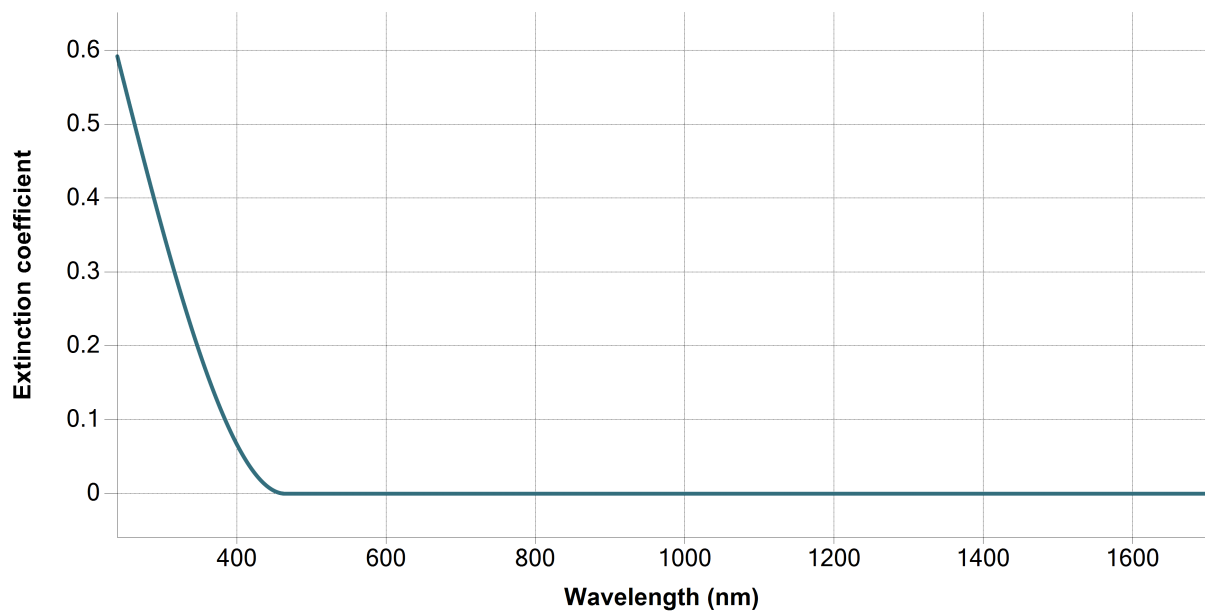
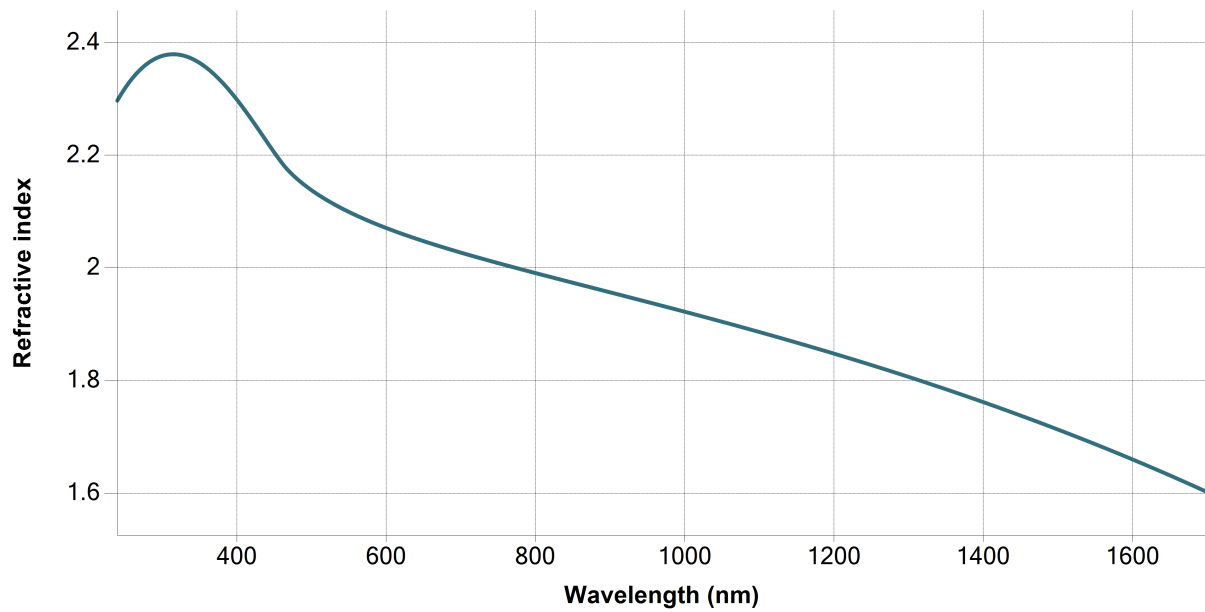
Regression graphs



Phase 2 (ITO + void) - Dispersion graphs



Phase 1 (ITO) - Dispersion graphs



Substrate (si) - Dispersion graphs



Correlation coefficients							
	Ph2 - ITO + void - Thickness	Ph1 - ITO - Thickness	Ph1 - Tauc- Lorentz[1] - A (eV)	Ph1 - Tauc- Lorentz[1] - E0 (eV)	Ph1 - Tauc- Lorentz[1] - C (eV)	Ph1 - Tauc- Lorentz[1] - Eg (eV)	Ph1 - Drude[2] - E_p (eV)
Ph2 - ITO + void - Thickness	1	-0.4681	-0.1233	0.0426	-0.1224	-0.034	-0.0892
Ph1 - ITO - Thickness		1	0.0263	0.0203	0.0559	0.0208	-0.2863
Ph1 - Tauc- Lorentz[1] - A (eV)			1	-0.2381	0.9679	0.8774	0.4441
Ph1 - Tauc- Lorentz[1] - E0 (eV)				1	0.0111	-0.5545	0.2216
Ph1 - Tauc- Lorentz[1] - C (eV)					1	0.7538	0.4965
Ph1 - Tauc- Lorentz[1] - Eg (eV)						1	0.2991
Ph1 - Drude[2] - E_p (eV)							1